United States Patent [19]

Ide et al.

[11] **Patent Number: Des. 312,047**

[45] **Date of Patent: ** Nov. 13, 1990**

[54] **ELECTRONIC THERMOMETER PROBE**

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[73] Assignee: **Terumo Kabushiki Kaisha,** Tokyo, Japan

[**] Term: **14 Years**

[21] Appl. No.: **152,582**

[22] Filed: **Feb. 5, 1988**

[30] **Foreign Application Priority Data**

Oct. 21, 1987 [JP] Japan 62-42745

[52] **U.S. Cl.** **D10/60**

[58] **Field of Search** D10/57, 60; 374/100, 374/106, 132, 151, 158, 159, 164, 170, 179, 185, 194, 208, 209; 128/236, 207.14

[56] **References Cited**

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[57] **CLAIM**

The ornamental design for a electronic thermometer probe, as shown.

DESCRIPTION

FIG. **1** is a front elevational view of a electronic thermometer probe showing our new design;
FIG. **2** is a left side elevational view;
FIG. **3** is a right side elevational view;
FIG. **4** is a rear elevational view;
FIG. **5** is a top plan view;
FIG. **6** is a bottom plan view; and
FIG. **7** is a cross-sectional view taken along line 7—7 of FIG. **1** thereof.

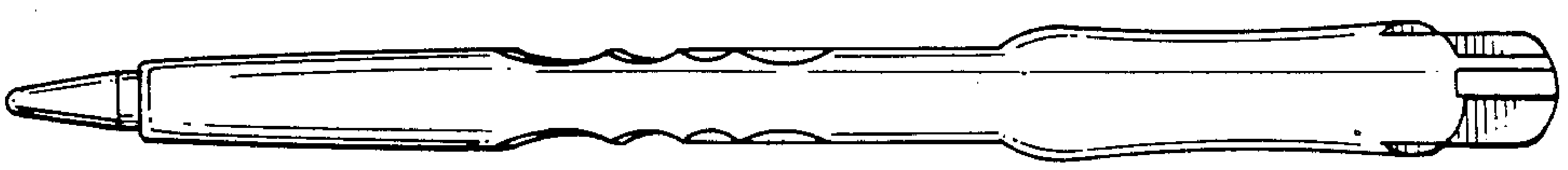

FIG. 1

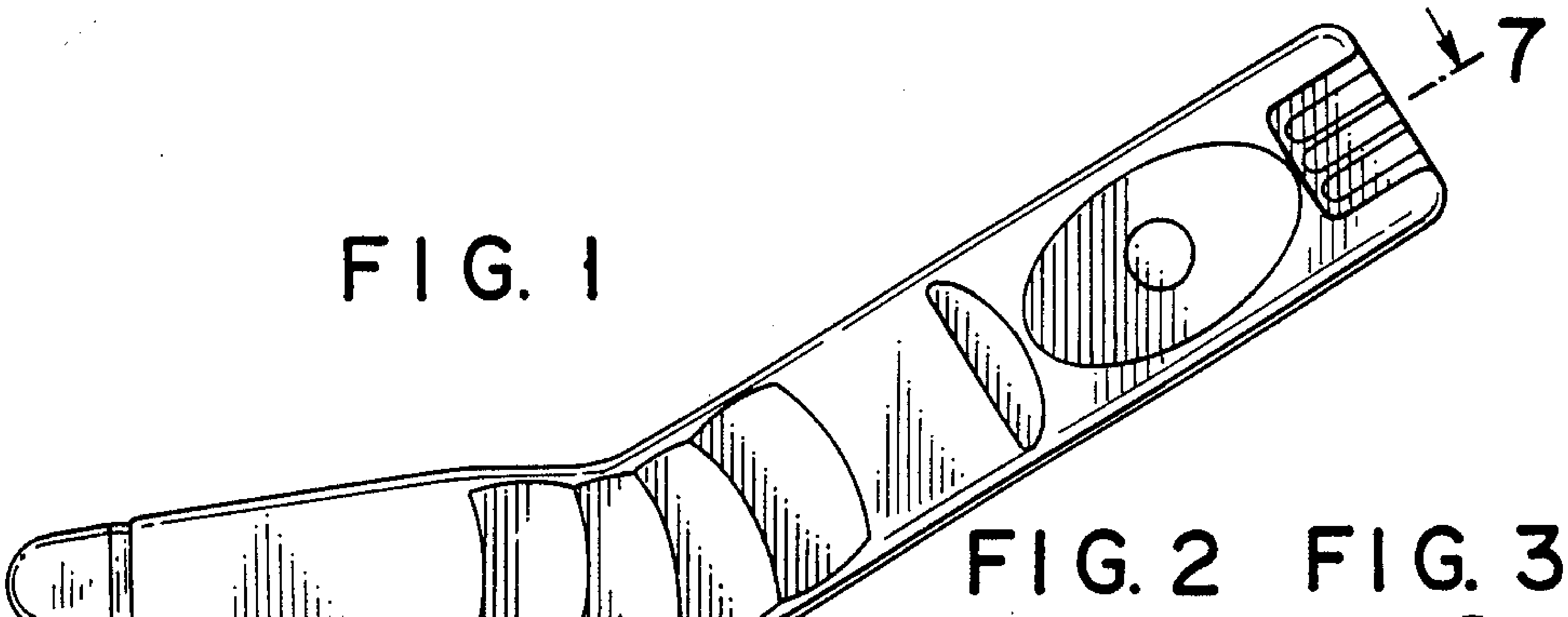

FIG. 2

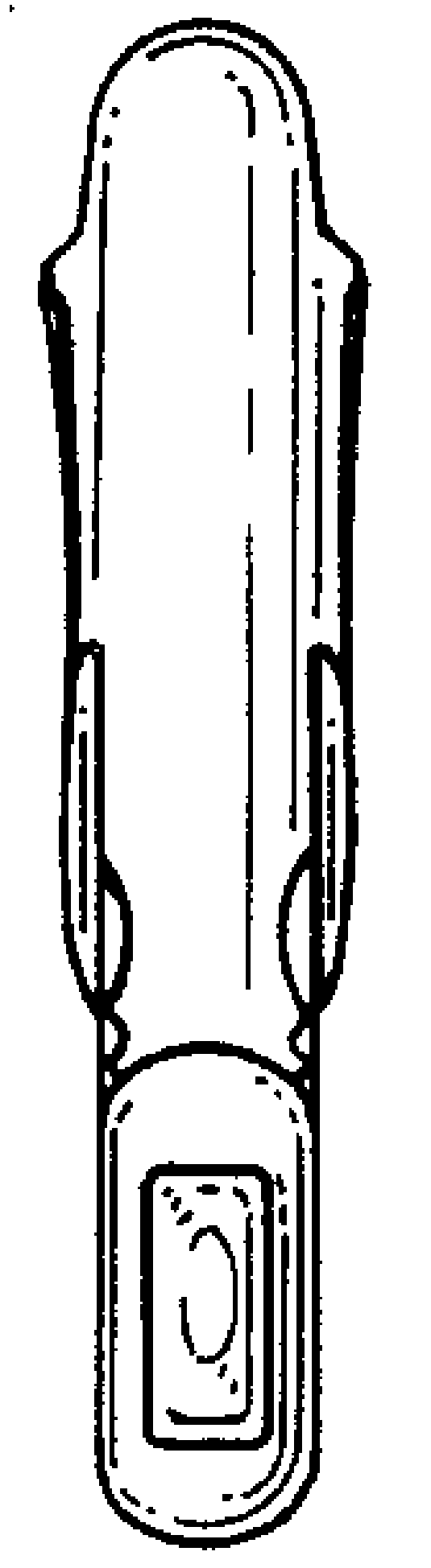

FIG. 3

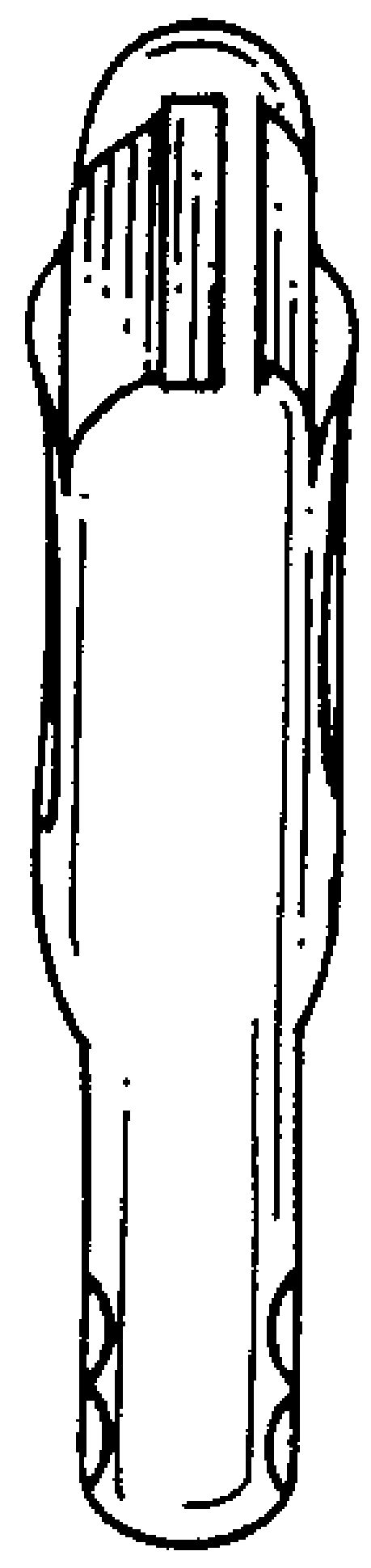

FIG. 4

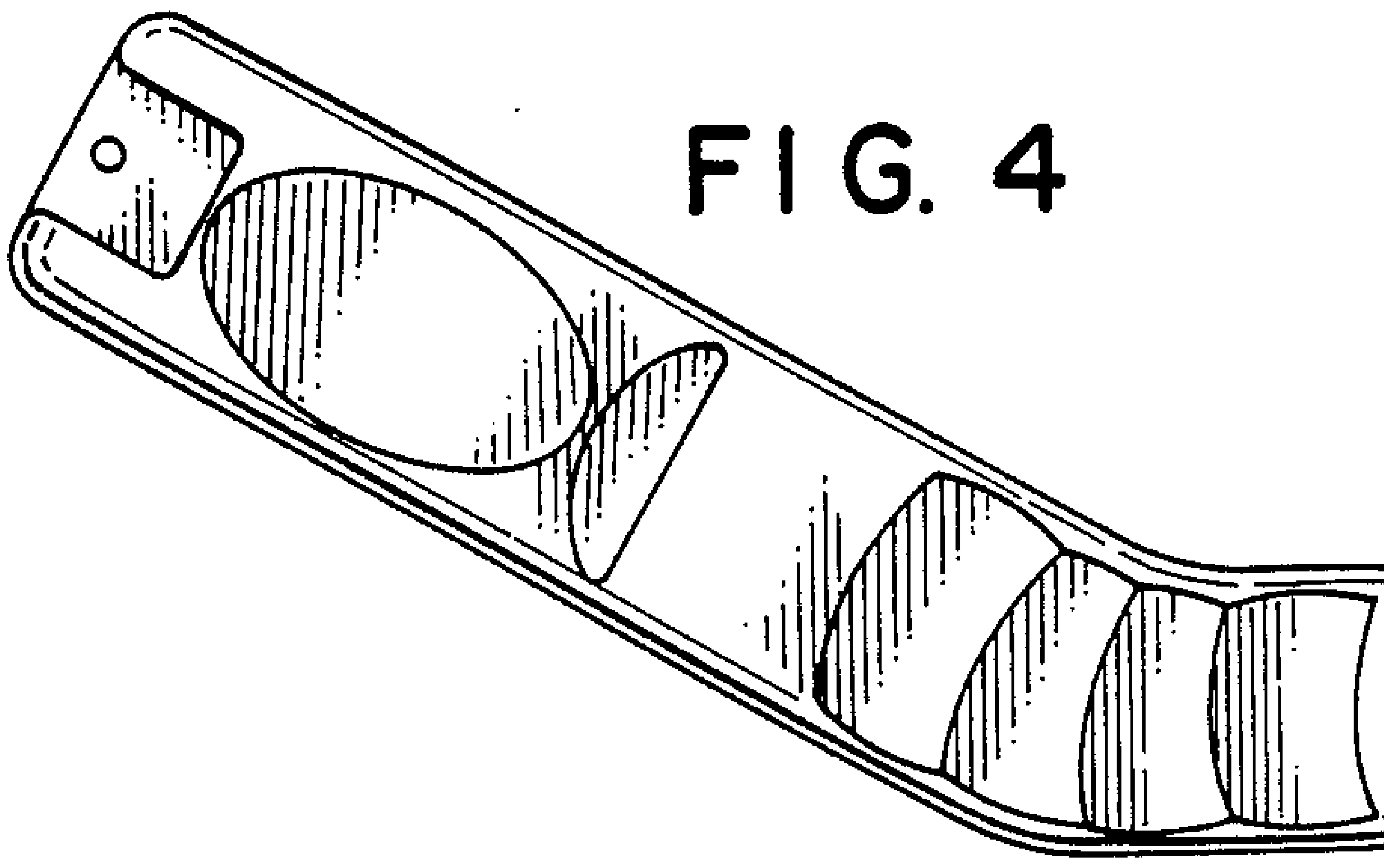

FIG. 5

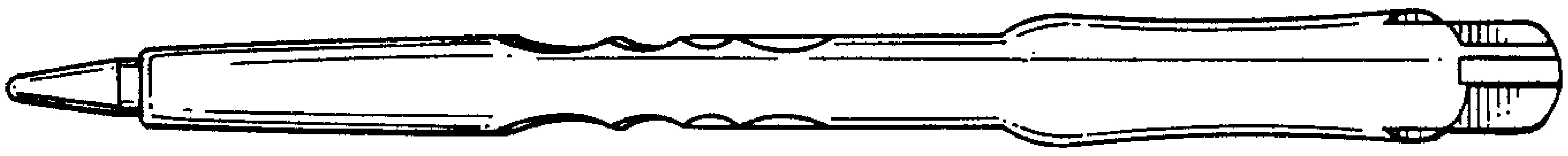

FIG. 6

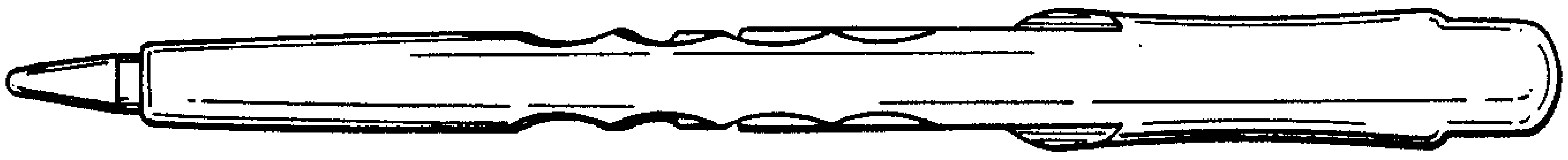

FIG. 7